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### Understanding [Embedded - CPLDs \(Complex Programmable Logic Devices\)](#)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

### Applications of Embedded - CPLDs

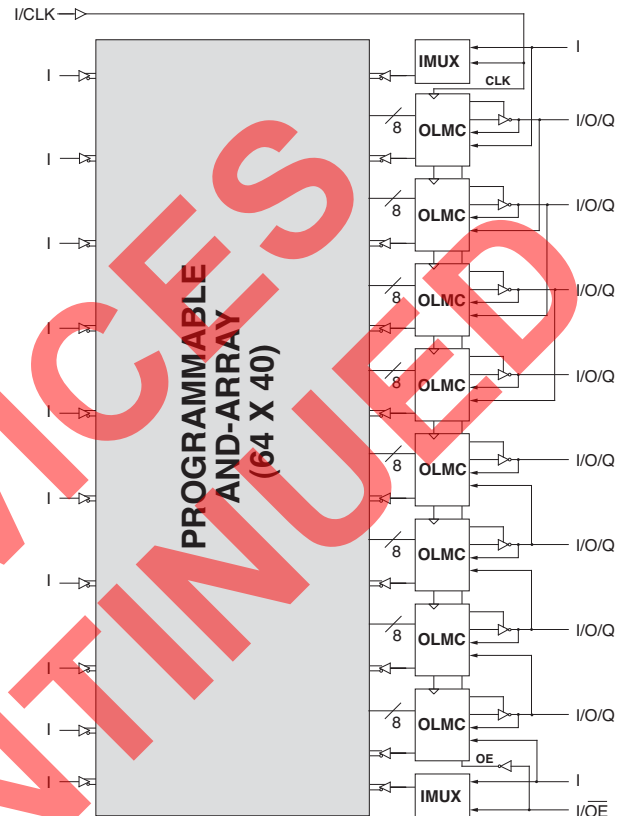
#### Details

Product Status	Obsolete
Programmable Type	EE PLD
Delay Time tpd(1) Max	25 ns
Voltage Supply - Internal	4.5V ~ 5.5V
Number of Logic Elements/Blocks	-
Number of Macrocells	8
Number of Gates	-
Number of I/O	-
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	28-LCC (J-Lead)
Supplier Device Package	28-PLCC (11.51x11.51)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/lattice-semiconductor/gal20v8b-25qjni">https://www.e-xfl.com/product-detail/lattice-semiconductor/gal20v8b-25qjni</a>

## Features

- **HIGH PERFORMANCE E<sup>2</sup>CMOS® TECHNOLOGY**
  - 5 ns Maximum Propagation Delay
  - $F_{max} = 166$  MHz
  - 4 ns Maximum from Clock Input to Data Output
  - UltraMOS® Advanced CMOS Technology
- **50% to 75% REDUCTION IN POWER FROM BIPOLAR**
  - 75mA Typ  $I_{cc}$  on Low Power Device
  - 45mA Typ  $I_{cc}$  on Quarter Power Device
- **ACTIVE PULL-UPS ON ALL PINS**
- **E<sup>2</sup> CELL TECHNOLOGY**
  - Reconfigurable Logic
  - Reprogrammable Cells
  - 100% Tested/100% Yields
  - High Speed Electrical Erasure (<100ms)
  - 20 Year Data Retention
- **EIGHT OUTPUT LOGIC MACROCELLS**
  - Maximum Flexibility for Complex Logic Designs
  - Programmable Output Polarity
  - Also Emulates 24-pin PAL® Devices with Full Function/Fuse Map/Parametric Compatibility
- **PRELOAD AND POWER-ON RESET OF ALL REGISTERS**
  - 100% Functional Testability
- **APPLICATIONS INCLUDE:**
  - DMA Control
  - State Machine Control
  - High Speed Graphics Processing
  - Standard Logic Speed Upgrade
- **ELECTRONIC SIGNATURE FOR IDENTIFICATION**
- **LEAD-FREE PACKAGE OPTIONS**

## Functional Block Diagram



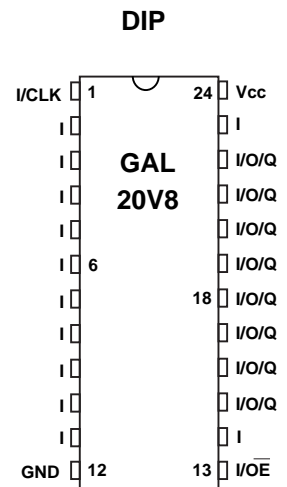
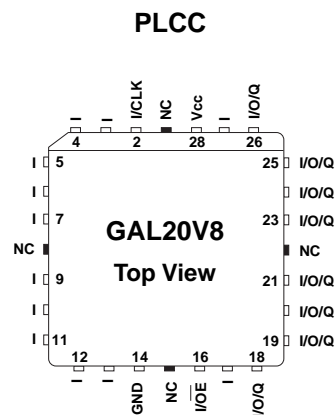
## Description

The GAL20V8C, at 5ns maximum propagation delay time, combines a high performance CMOS process with Electrically Erasable (E<sup>2</sup>) floating gate technology to provide the highest speed performance available in the PLD market. High speed erase times (<100ms) allow the devices to be reprogrammed quickly and efficiently.

The generic architecture provides maximum design flexibility by allowing the Output Logic Macrocell (OLMC) to be configured by the user. An important subset of the many architecture configurations possible with the GAL20V8 are the PAL architectures listed in the table of the macrocell description section. GAL20V8 devices are capable of emulating any of these PAL architectures with full function/fuse map/parametric compatibility.

Unique test circuitry and reprogrammable cells allow complete AC, DC, and functional testing during manufacture. As a result, Lattice Semiconductor delivers 100% field programmability and functionality of all GAL products. In addition, 100 erase/write cycles and data retention in excess of 20 years are specified.

## Pin Configuration



## GAL20V8 Ordering Information

### Conventional Packaging Commercial Grade Specifications

Tpd (ns)	Tsu (ns)	Tco (ns)	Icc (mA)	Ordering #	Package
5	3	4	115	GAL20V8C-5LJ <sup>1</sup>	28-Lead PLCC
7.5	7	5	115	GAL20V8C-7LJ	28-Lead PLCC
			115	GAL20V8B-7LP <sup>1</sup>	24-Pin Plastic DIP
10	10	7	115	GAL20V8C-10LJ	28-Lead PLCC
			115	GAL20V8B-10LP	24-Pin Plastic DIP
15	12	10	55	GAL20V8B-15QP	24-Pin Plastic DIP
			55	GAL20V8B-15QJ	28-Lead PLCC
			90	GAL20V8B-15LP	24-Pin Plastic DIP
			90	GAL20V8B-15LJ	28-Lead PLCC
25	15	12	55	GAL20V8B-25QP	24-Pin Plastic DIP
			55	GAL20V8B-25QJ	28-Lead PLCC
			90	GAL20V8B-25LP	24-Pin Plastic DIP
			90	GAL20V8B-25LJ	28-Lead PLCC

### Industrial Grade Specifications

Tpd (ns)	Tsu (ns)	Tco (ns)	Icc (mA)	Ordering #	Package
10	10	7	130	GAL20V8C-10LJI	28-Lead PLCC
			130	GAL20V8B-10LPI <sup>1</sup>	24-Pin Plastic DIP
			130	GAL20V8B-10LJI	28-Lead PLCC
15	12	10	130	GAL20V8B-15LPI	24-Pin Plastic DIP
			130	GAL20V8B-15LJI	28-Lead PLCC
20	13	11	65	GAL20V8B-20QPI	24-Pin Plastic DIP
			65	GAL20V8B-20QJI	28-Lead PLCC
25	15	12	65	GAL20V8B-25QPI	24-Pin Plastic DIP
			65	GAL20V8B-25QJI	28-Lead PLCC
			130	GAL20V8B-25LPI	24-Pin Plastic DIP
			130	GAL20V8B-25LJI	28-Lead PLCC

1. Discontinued per PCN #06-07. Contact Rochester Electronics for available inventory.

## Registered Mode

In the Registered mode, macrocells are configured as dedicated registered outputs or as I/O functions.

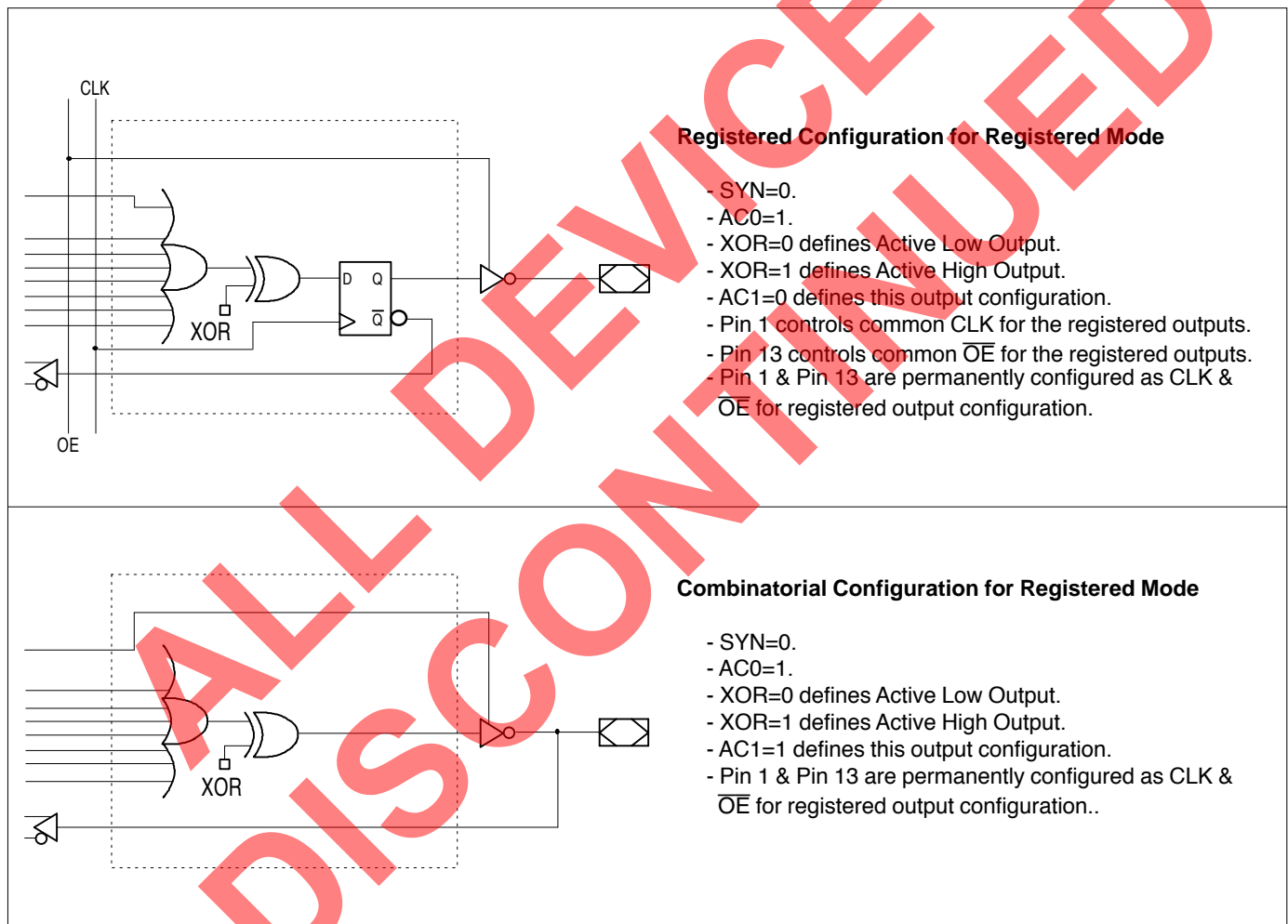
Architecture configurations available in this mode are similar to the common 20R8 and 20RP4 devices with various permutations of polarity, I/O and register placement.

All registered macrocells share common clock and output enable control pins. Any macrocell can be configured as registered or I/O. Up to eight registers or up to eight I/Os are possible in this mode.

Dedicated input or output functions can be implemented as subsets of the I/O function.

Registered outputs have eight product terms per output. I/Os have seven product terms per output.

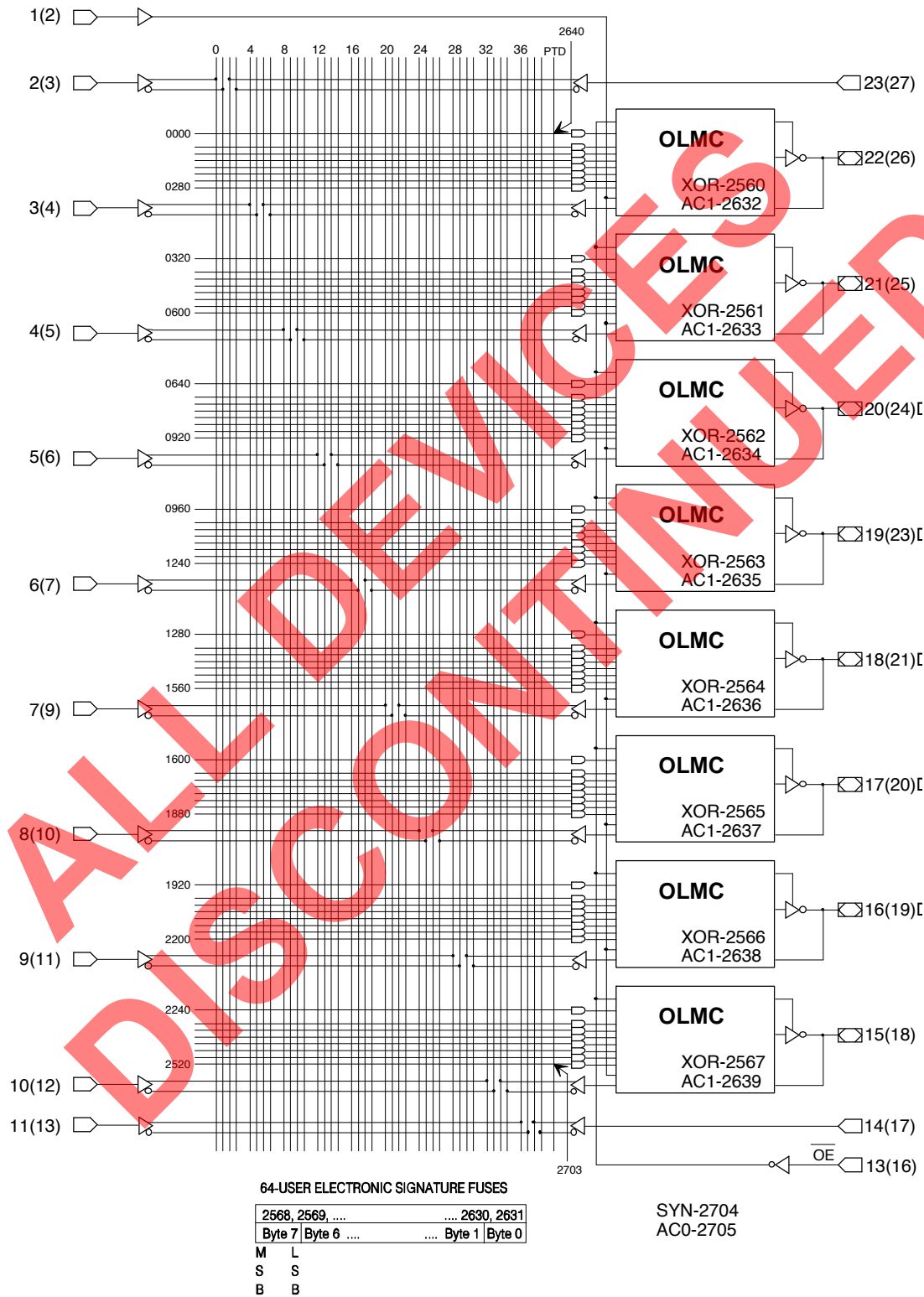
The JEDEC fuse numbers, including the User Electronic Signature (UES) fuses and the Product Term Disable (PTD) fuses, are shown on the logic diagram on the following page.



Note: The development software configures all of the architecture control bits and checks for proper pin usage automatically.

**Registered Mode Logic Diagram**

**DIP (PLCC) Package Pinouts**



## Complex Mode

In the Complex mode, macrocells are configured as output only or I/O functions.

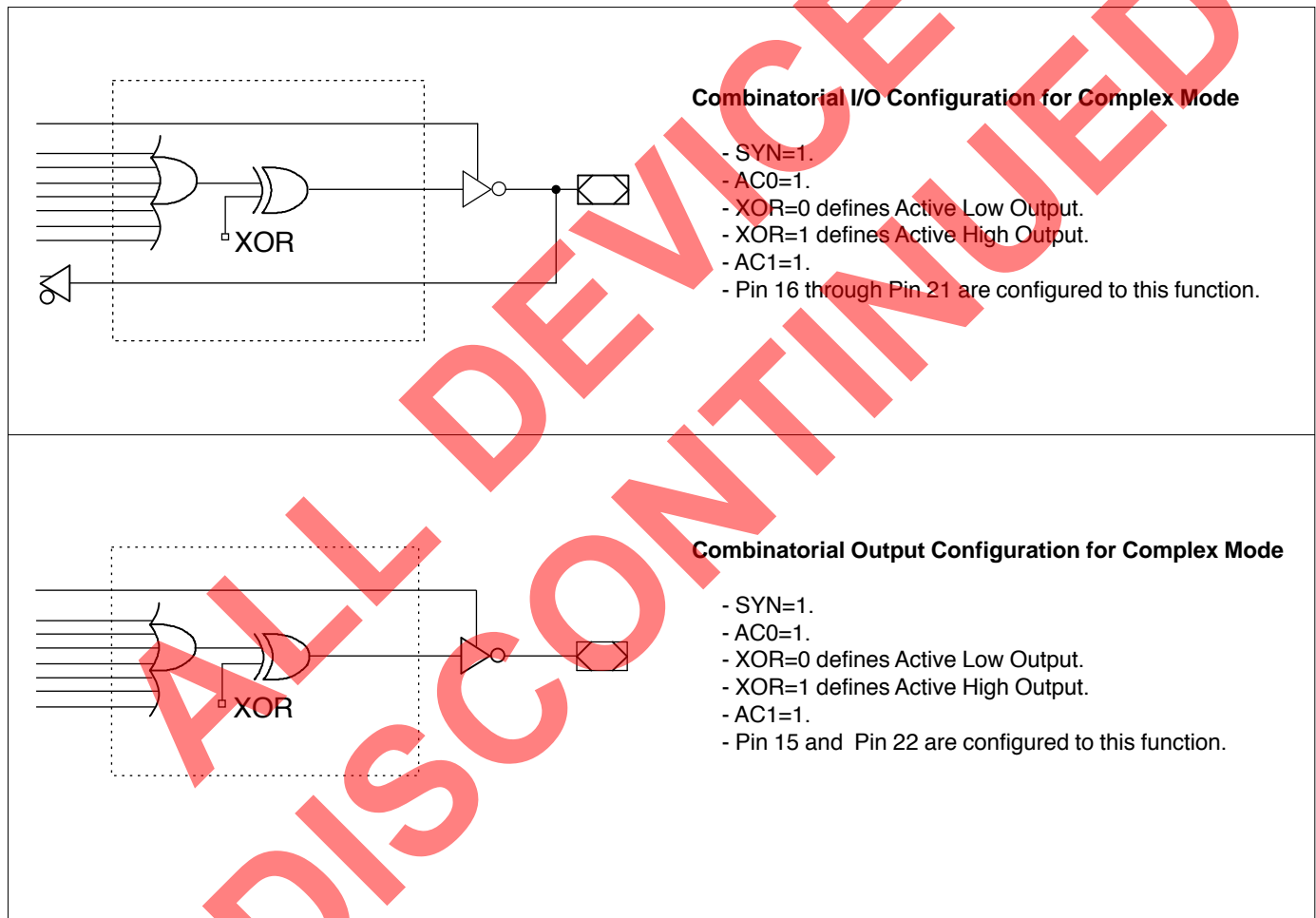
Architecture configurations available in this mode are similar to the common 20L8 and 20P8 devices with programmable polarity in each macrocell.

Up to six I/Os are possible in this mode. Dedicated inputs or outputs can be implemented as subsets of the I/O function. The two outer most macrocells (pins 15 & 22) do not have input capability. De-

signs requiring eight I/Os can be implemented in the Registered mode.

All macrocells have seven product terms per output. One product term is used for programmable output enable control. Pins 1 and 13 are always available as data inputs into the AND array.

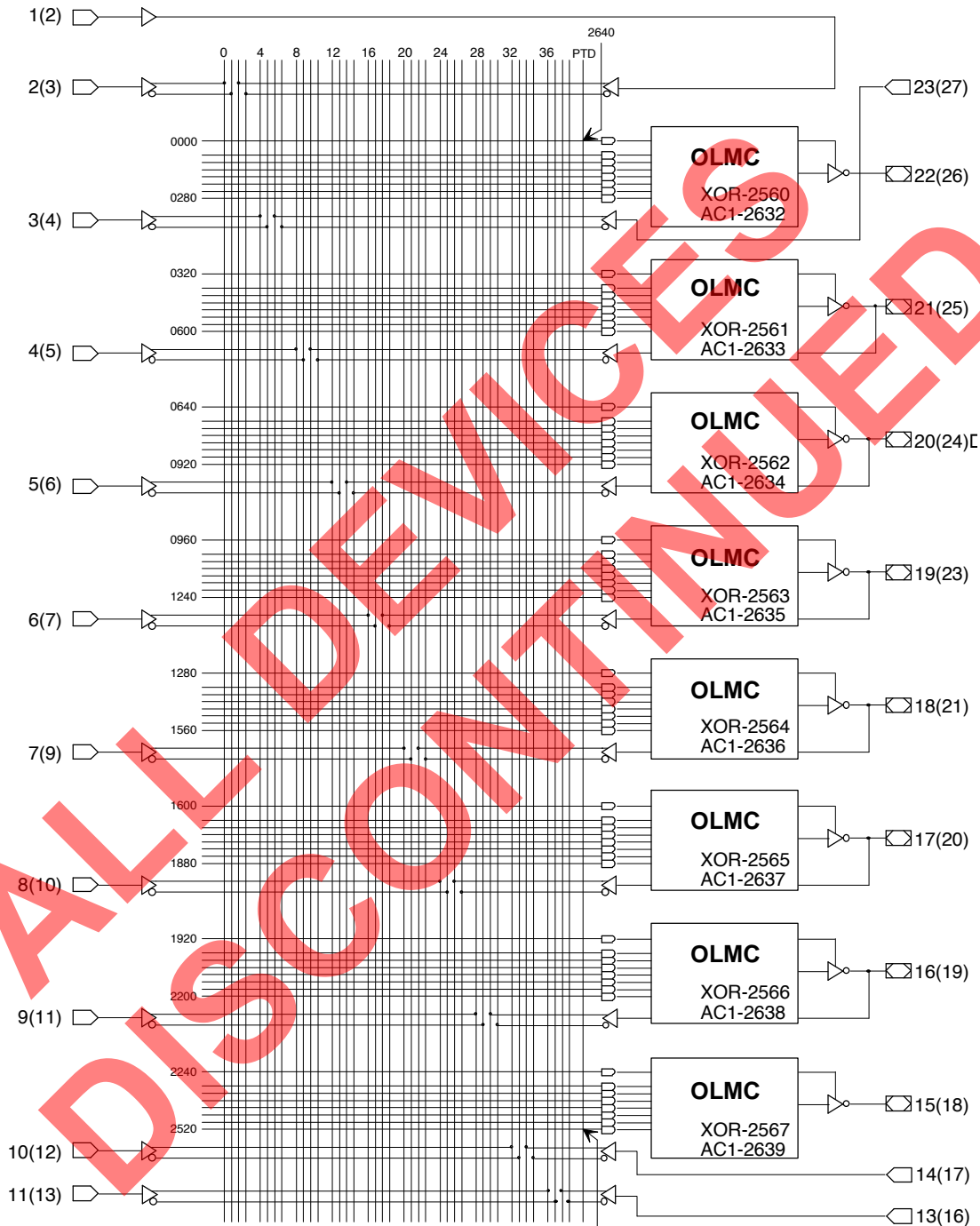
The JEDEC fuse numbers including the UES fuses and PTD fuses are shown on the logic diagram on the following page.



Note: The development software configures all of the architecture control bits and checks for proper pin usage automatically.

**Complex Mode Logic Diagram**

**DIP (PLCC) Package Pinouts**



**64-USER ELECTRONIC SIGNATURE FUSES**

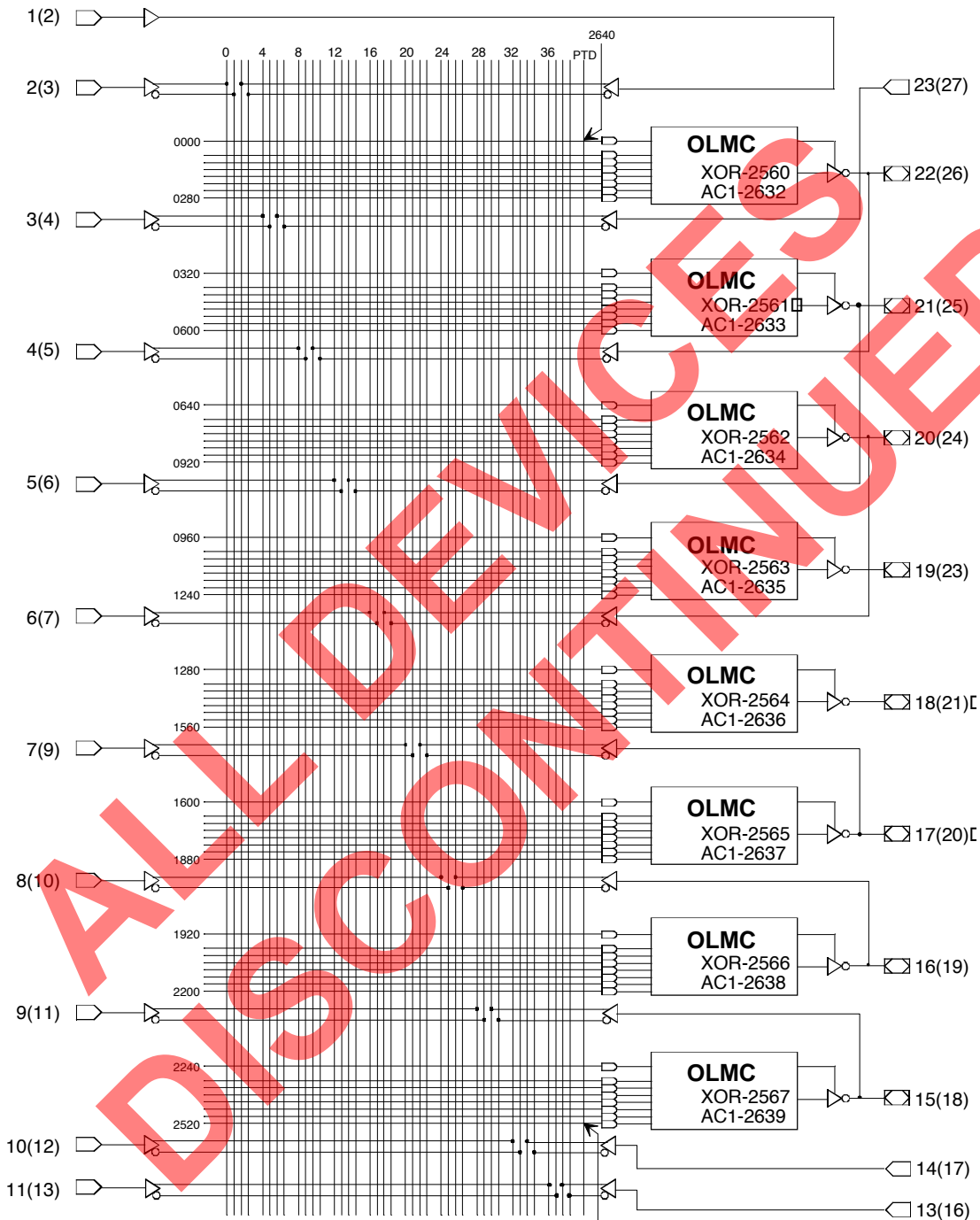
2568, 2569, ....	.... 2630, 2631
Byte 7 Byte 6 ....	.... Byte 1 Byte 0

M L  
S S  
B B

SYN-2704  
AC0-2705

**Simple Mode Logic Diagram**

**DIP (PLCC) Package Pinouts**



**64-USER ELECTRONIC SIGNATURE FUSES**

2568, 2569, ....	.... 2630, 2631
Byte 7 Byte 6 ....	.... Byte 1 Byte 0
M L	
S S	
B B	

SYN-2704  
AC0-2705



## Absolute Maximum Ratings<sup>(1)</sup>

Supply voltage  $V_{CC}$  ..... -0.5 to +7V  
 Input voltage applied ..... -2.5 to  $V_{CC} + 1.0V$   
 Off-state output voltage applied ..... -2.5 to  $V_{CC} + 1.0V$   
 Storage Temperature ..... -65 to 150°C  
 Ambient Temperature with

Power Applied ..... -55 to 125°C

1. Stresses above those listed under the "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress only ratings and functional operation of the device at these or at any other conditions above those indicated in the operational sections of this specification is not implied (while programming, follow the programming specifications).

## Recommended Operating Conditions

### Commercial Devices:

Ambient Temperature ( $T_A$ ) ..... 0 to 75°C  
 Supply voltage ( $V_{CC}$ )  
 with Respect to Ground ..... +4.75 to +5.25V

### Industrial Devices:

Ambient Temperature ( $T_A$ ) ..... -40 to 85°C  
 Supply voltage ( $V_{CC}$ )  
 with Respect to Ground ..... +4.50 to +5.50V

## DC Electrical Characteristics

Over Recommended Operating Conditions (Unless Otherwise Specified)

SYMBOL	PARAMETER	CONDITION	MIN.	TYP. <sup>3</sup>	MAX.	UNITS
$V_{IL}$	Input Low Voltage		$V_{SS} - 0.5$	—	0.8	V
$V_{IH}$	Input High Voltage		2.0	—	$V_{CC} + 1$	V
$I_{IL}^1$	Input or I/O Low Leakage Current	$0V \leq V_{IN} \leq V_{IL} (MAX.)$	—	—	-100	$\mu A$
$I_{IH}$	Input or I/O High Leakage Current	$3.5V \leq V_{IN} \leq V_{CC}$	—	—	10	$\mu A$
$V_{OL}$	Output Low Voltage	$I_{OL} = MAX.$ $V_{IN} = V_{IL}$ or $V_{IH}$	—	—	0.5	V
$V_{OH}$	Output High Voltage	$I_{OH} = MAX.$ $V_{IN} = V_{IL}$ or $V_{IH}$	2.4	—	—	V
$I_{OL}$	Low Level Output Current		—	—	16	mA
$I_{OH}$	High Level Output Current		—	—	-3.2	mA
$I_{OS}^2$	Output Short Circuit Current	$V_{CC} = 5V$ $V_{OUT} = 0.5V$ $T_A = 25^\circ C$	-30	—	-150	mA

### COMMERCIAL

$I_{CC}$	Operating Power Supply Current	$V_{IL} = 0.5V$ $V_{IH} = 3.0V$ $f_{toggle} = 15MHz$ Outputs Open	L -5/-7/-10	—	75	115	mA
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### INDUSTRIAL

$I_{CC}$	Operating Power Supply Current	$V_{IL} = 0.5V$ $V_{IH} = 3.0V$ $f_{toggle} = 15MHz$ Outputs Open	L-10	—	75	130	mA
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1) The leakage current is due to the internal pull-up resistor on all pins. See **Input Buffer** section for more information.

2) One output at a time for a maximum duration of one second.  $V_{out} = 0.5V$  was selected to avoid test problems caused by tester ground degradation. Characterized but not 100% tested.

3) Typical values are at  $V_{CC} = 5V$  and  $T_A = 25^\circ C$

## AC Switching Characteristics

Over Recommended Operating Conditions

				COM		COM		COM/IND		
PARAMETER	TEST COND <sup>1</sup> .	DESCRIPTION		-5		-7		-10		UNITS
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
<b>t<sub>pd</sub></b>	A	Input or I/O to	8 outputs switching	1	5	3	7.5	3	10	ns
		Comb. Output	1 output switching	—	—	—	7	—	—	ns
<b>t<sub>co</sub></b>	A	Clock to Output Delay		1	4	2	5	2	7	ns
<b>t<sub>cf</sub><sup>2</sup></b>	—	Clock to Feedback Delay		—	3	—	3	—	6	ns
<b>t<sub>su</sub></b>	—	Setup Time, Input or Feedback before Clock↑		3	—	5	—	7.5	—	ns
<b>t<sub>h</sub></b>	—	Hold Time, Input or Feedback after Clock↑		0	—	0	—	0	—	ns
<b>f<sub>max</sub><sup>3</sup></b>	A	Maximum Clock Frequency with External Feedback, 1/(t <sub>su</sub> + t <sub>co</sub> )		142.8	—	100	—	66.7	—	MHz
	A	Maximum Clock Frequency with Internal Feedback, 1/(t <sub>su</sub> + t <sub>cf</sub> )		166	—	125	—	71.4	—	MHz
	A	Maximum Clock Frequency with No Feedback		166	—	125	—	83.3	—	MHz
<b>t<sub>wh</sub></b>	—	Clock Pulse Duration, High		3	—	4	—	6	—	ns
<b>t<sub>wl</sub></b>	—	Clock Pulse Duration, Low		3	—	4	—	6	—	ns
<b>t<sub>en</sub></b>	B	Input or I/O to Output Enabled		1	6	3	9	3	10	ns
	B	OE to Output Enabled		1	6	2	6	2	10	ns
<b>t<sub>dis</sub></b>	C	Input or I/O to Output Disabled		1	5	2	9	2	10	ns
	C	OE to Output Disabled		1	5	1.5	6	1.5	10	ns

1) Refer to **Switching Test Conditions** section.

2) Calculated from f<sub>max</sub> with internal feedback. Refer to **f<sub>max</sub> Descriptions** section.

3) Refer to **f<sub>max</sub> Descriptions** section. Characterized initially and after any design or process changes that may affect these parameters.

## Capacitance (T<sub>A</sub> = 25°C, f = 1.0 MHz)

SYMBOL	PARAMETER	MAXIMUM*	UNITS	TEST CONDITIONS
C <sub>I</sub>	Input Capacitance	8	pF	V <sub>CC</sub> = 5.0V, V <sub>I</sub> = 2.0V
C <sub>I/O</sub>	I/O Capacitance	8	pF	V <sub>CC</sub> = 5.0V, V <sub>I/O</sub> = 2.0V

\*Characterized but not 100% tested

## Absolute Maximum Ratings<sup>(1)</sup>

Supply voltage  $V_{CC}$  ..... -0.5 to +7V  
 Input voltage applied ..... -2.5 to  $V_{CC} + 1.0V$   
 Off-state output voltage applied ..... -2.5 to  $V_{CC} + 1.0V$   
 Storage Temperature ..... -65 to 150°C  
 Ambient Temperature with

Power Applied ..... -55 to 125°C

1. Stresses above those listed under the "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress only ratings and functional operation of the device at these or at any other conditions above those indicated in the operational sections of this specification is not implied (while programming, follow the programming specifications).

## Recommended Operating Conditions

### Commercial Devices:

Ambient Temperature ( $T_A$ ) ..... 0 to 75°C

Supply voltage ( $V_{CC}$ )

with Respect to Ground ..... +4.75 to +5.25V

### Industrial Devices:

Ambient Temperature ( $T_A$ ) ..... -40 to 85°C

Supply voltage ( $V_{CC}$ )

with Respect to Ground ..... +4.50 to +5.50V

## DC Electrical Characteristics

Over Recommended Operating Conditions (Unless Otherwise Specified)

SYMBOL	PARAMETER	CONDITION	MIN.	TYP. <sup>3</sup>	MAX.	UNITS
<b>V<sub>IL</sub></b>	Input Low Voltage		$V_{SS} - 0.5$	—	0.8	V
<b>V<sub>IH</sub></b>	Input High Voltage		2.0	—	$V_{CC} + 1$	V
<b>I<sub>IL</sub><sup>1</sup></b>	Input or I/O Low Leakage Current	$0V \leq V_{IN} \leq V_{IL} (MAX.)$	—	—	-100	μA
<b>I<sub>IH</sub></b>	Input or I/O High Leakage Current	$3.5V \leq V_{IN} \leq V_{CC}$	—	—	10	μA
<b>V<sub>OL</sub></b>	Output Low Voltage	$I_{OL} = MAX.$ $V_{IN} = V_{IL}$ or $V_{IH}$	—	—	0.5	V
<b>V<sub>OH</sub></b>	Output High Voltage	$I_{OH} = MAX.$ $V_{IN} = V_{IL}$ or $V_{IH}$	2.4	—	—	V
<b>I<sub>OL</sub></b>	Low Level Output Current		—	—	24	mA
<b>I<sub>OH</sub></b>	High Level Output Current		—	—	-3.2	mA
<b>I<sub>OS</sub><sup>2</sup></b>	Output Short Circuit Current	$V_{CC} = 5V$ $V_{OUT} = 0.5V$ $T_A = 25^\circ C$	-30	—	-150	mA

### COMMERCIAL

<b>I<sub>CC</sub></b>	Operating Power Supply Current	$V_{IL} = 0.5V$ $V_{IH} = 3.0V$ $f_{toggle} = 15MHz$ Outputs Open	<b>L</b> -7/-10	—	75	115	mA
			<b>L</b> -15/-25	—	75	90	mA
			<b>Q</b> -15/-25	—	45	55	mA

### INDUSTRIAL

<b>I<sub>CC</sub></b>	Operating Power Supply Current	$V_{IL} = 0.5V$ $V_{IH} = 3.0V$ $f_{toggle} = 15MHz$ Outputs Open	<b>L</b> -10/-15/-25	—	75	130	mA
			<b>Q</b> -20/-25	—	45	65	mA

1) The leakage current is due to the internal pull-up resistor on all pins. See **Input Buffer** section for more information.

2) One output at a time for a maximum duration of one second.  $V_{out} = 0.5V$  was selected to avoid test problems caused by tester ground degradation. Characterized but not 100% tested.

3) Typical values are at  $V_{CC} = 5V$  and  $T_A = 25^\circ C$

## AC Switching Characteristics

Over Recommended Operating Conditions

				COM		COM / IND		COM / IND		IND		COM / IND		
PARAM.	TEST COND <sup>1</sup> .	DESCRIPTION		-7		-10		-15		-20		-25		UNITS
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
<b>t<sub>pd</sub></b>	A	Input or I/O to Comb. Output	8 outputs switching	3	7.5	3	10	3	15	3	20	3	25	ns
			1 output switching	—	7	—	—	—	—	—	—	—	—	ns
<b>t<sub>co</sub></b>	A	Clock to Output Delay		2	5	2	7	2	10	2	11	2	12	ns
<b>t<sub>cf</sub><sup>2</sup></b>	—	Clock to Feedback Delay		—	3	—	6	—	8	—	9	—	10	ns
<b>t<sub>su</sub></b>	—	Setup Time, Input or Fdbk before Clk↑		7	—	10	—	12	—	13	—	15	—	ns
<b>t<sub>h</sub></b>	—	Hold Time, Input or Fdbk after Clk↑		0	—	0	—	0	—	0	—	0	—	ns
<b>f<sub>max</sub><sup>3</sup></b>	A	Maximum Clock Frequency with External Feedback, 1/(t <sub>su</sub> + t <sub>co</sub> )		83.3	—	58.8	—	45.5	—	41.6	—	37	—	MHz
	A	Maximum Clock Frequency with Internal Feedback, 1/(t <sub>su</sub> + t <sub>cf</sub> )		100	—	62.5	—	50	—	45.4	—	40	—	MHz
	A	Maximum Clock Frequency with No Feedback		100	—	62.5	—	62.5	—	50	—	41.7	—	MHz
<b>t<sub>wh</sub></b>	—	Clock Pulse Duration, High		5	—	8	—	8	—	10	—	12	—	ns
<b>t<sub>wl</sub></b>	—	Clock Pulse Duration, Low		5	—	8	—	8	—	10	—	12	—	ns
<b>t<sub>en</sub></b>	B	Input or I/O to Output Enabled		3	9	3	10	—	15	—	18	—	25	ns
	B	$\overline{OE}$ to Output Enabled		2	6	2	10	—	15	—	18	—	20	ns
<b>t<sub>dis</sub></b>	C	Input or I/O to Output Disabled		2	9	2	10	—	15	—	18	—	25	ns
	C	$\overline{OE}$ to Output Disabled		1.5	6	1.5	10	—	15	—	18	—	20	ns

1) Refer to **Switching Test Conditions** section.

2) Calculated from f<sub>max</sub> with internal feedback. Refer to **f<sub>max</sub> Descriptions** section.

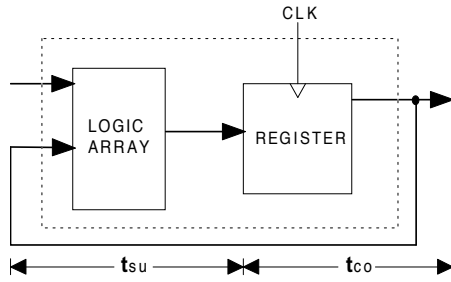
3) Refer to **f<sub>max</sub> Descriptions** section.

## Capacitance (T<sub>A</sub> = 25°C, f = 1.0 MHz)

SYMBOL	PARAMETER	MAXIMUM*	UNITS	TEST CONDITIONS
C <sub>I</sub>	Input Capacitance	8	pF	V <sub>CC</sub> = 5.0V, V <sub>I</sub> = 2.0V
C <sub>I/O</sub>	I/O Capacitance	8	pF	V <sub>CC</sub> = 5.0V, V <sub>I/O</sub> = 2.0V

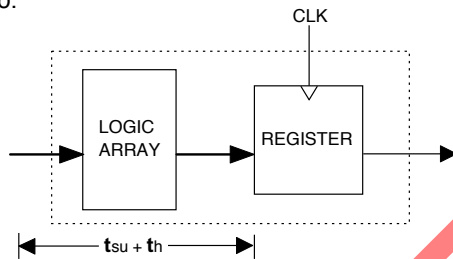
\*Characterized but not 100% tested.

## fmax Descriptions



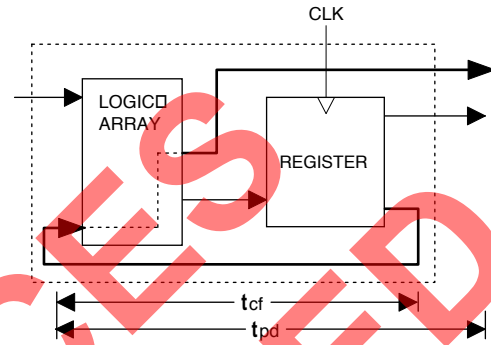
**fmax with External Feedback  $1/(t_{su}+t_{co})$**

**Note:** fmax with external feedback is calculated from measured tsu and tco.



**fmax with No Feedback**

**Note:** fmax with no feedback may be less than  $1/(t_{wh} + t_{wl})$ . This is to allow for a clock duty cycle of other than 50%.



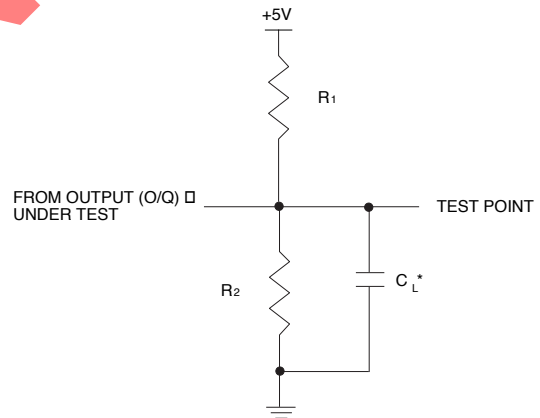
**fmax with Internal Feedback  $1/(t_{su}+t_{cf})$**

**Note:** tcf is a calculated value, derived by subtracting tsu from the period of fmax w/internal feedback ( $t_{cf} = 1/f_{max} - t_{su}$ ). The value of tcf is used primarily when calculating the delay from clocking a register to a combinational output (through registered feedback), as shown above. For example, the timing from clock to a combinational output is equal to  $t_{cf} + t_{pd}$ .

## Switching Test Conditions

Input Pulse Levels		GND to 3.0V
Input Rise and Fall Times	GAL20V8B	2 – 3ns 10% – 90%
	GAL20V8C	1.5ns 10% – 90%
Input Timing Reference Levels		1.5V
Output Timing Reference Levels		1.5V
Output Load		See Figure

3-state levels are measured 0.5V from steady-state active level.



\*CL INCLUDES TEST FIXTURE AND PROBE CAPACITANCE

### GAL20V8B Output Load Conditions (see figure)

Test Condition		R1	R2	CL
A		200Ω	390Ω	50pF
B	Active High	∞	390Ω	50pF
	Active Low	200Ω	390Ω	50pF
C	Active High	∞	390Ω	5pF
	Active Low	200Ω	390Ω	5pF

### GAL20V8C Output Load Conditions (see figure)

Test Condition		R1	R2	CL
A		200Ω	200Ω	50pF
B	Active High	∞	200Ω	50pF
	Active Low	200Ω	200Ω	50pF
C	Active High	∞	200Ω	5pF
	Active Low	200Ω	200Ω	5pF

## Electronic Signature

An electronic signature is provided in every GAL20V8 device. It contains 64 bits of reprogrammable memory that can contain user defined data. Some uses include user ID codes, revision numbers, or inventory control. The signature data is always available to the user independent of the state of the security cell.

NOTE: The electronic signature is included in checksum calculations. Changing the electronic signature will alter the checksum.

## Security Cell

A security cell is provided in the GAL20V8 devices to prevent unauthorized copying of the array patterns. Once programmed, this cell prevents further read access to the functional bits in the device. This cell can only be erased by re-programming the device, so the original configuration can never be examined once this cell is programmed. The Electronic Signature is always available to the user, regardless of the state of this control cell.

## Latch-Up Protection

GAL20V8 devices are designed with an on-board charge pump to negatively bias the substrate. The negative bias minimizes the potential of latch-up caused by negative input undershoots. Additionally, outputs are designed with n-channel pull-ups instead of the traditional p-channel pull-ups in order to eliminate latch-up due to output overshoots.

## Device Programming

GAL devices are programmed using a Lattice Semiconductor-approved Logic Programmer, available from a number of manufacturers. Complete programming of the device takes only a few seconds. Erasing of the device is transparent to the user, and is done automatically as part of the programming cycle.

## Output Register Preload

When testing state machine designs, all possible states and state transitions must be verified in the design, not just those required in the normal machine operations. This is because, in system operation, certain events occur that may throw the logic into an illegal state (power-up, line voltage glitches, brown-outs, etc.). To test a design for proper treatment of these conditions, a way must be provided to break the feedback paths, and force any desired (i.e., illegal) state into the registers. Then the machine can be sequenced and the outputs tested for correct next state conditions.

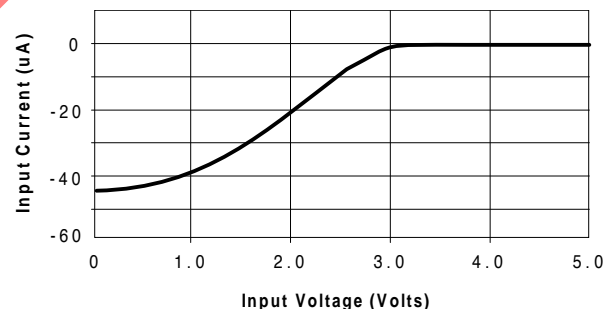
GAL20V8 devices include circuitry that allows each registered output to be synchronously set either high or low. Thus, any present state condition can be forced for test sequencing. If necessary, approved GAL programmers capable of executing test vectors perform output register preload automatically.

## Input Buffers

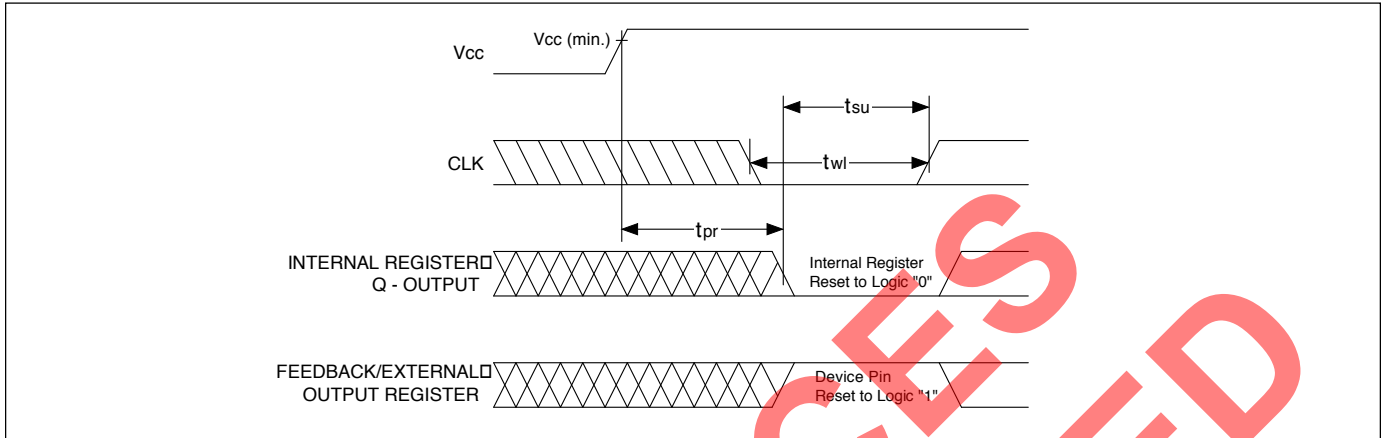
GAL20V8 devices are designed with TTL level compatible input buffers. These buffers have a characteristically high impedance, and present a much lighter load to the driving logic than bipolar TTL devices.

The GAL20V8 input and I/O pins have built-in active pull-ups. As a result, unused inputs and I/O's will float to a TTL "high" (logical "1"). Lattice Semiconductor recommends that all unused inputs and tri-stated I/O pins be connected to another active input, V<sub>CC</sub>, or Ground. Doing this will tend to improve noise immunity and reduce I<sub>CC</sub> for the device.

Typical Input Pull-up Characteristic



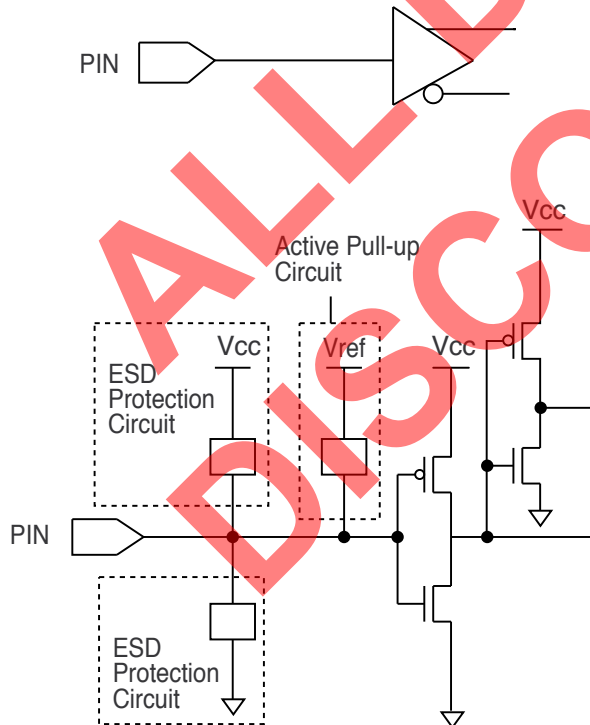
## Power-Up Reset



Circuitry within the GAL20V8 provides a reset signal to all registers during power-up. All internal registers will have their Q outputs set low after a specified time ( $t_{pr}$ , 1  $\mu$ s MAX). As a result, the state on the registered output pins (if they are enabled) will always be high on power-up, regardless of the programmed polarity of the output pins. This feature can greatly simplify state machine design by providing a known state on power-up. Because of the asynchronous nature of system power-up, some conditions must be met to provide

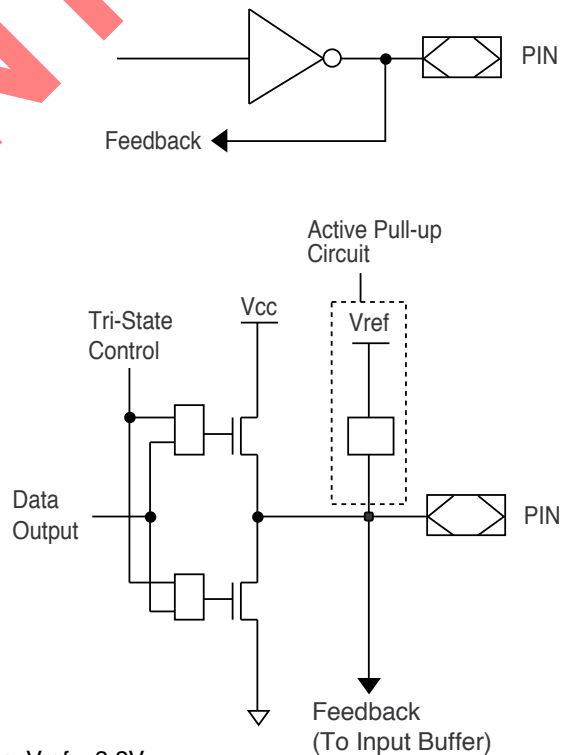
a valid power-up reset of the device. First, the  $V_{CC}$  rise must be monotonic. Second, the clock input must be at static TTL level as shown in the diagram during power up. The registers will reset within a maximum of  $t_{pr}$  time. As in normal system operation, avoid clocking the device until all input and feedback path setup times have been met. The clock must also meet the minimum pulse width requirements.

## Input/Output Equivalent Schematics



Typ.  $V_{ref} = 3.2V$

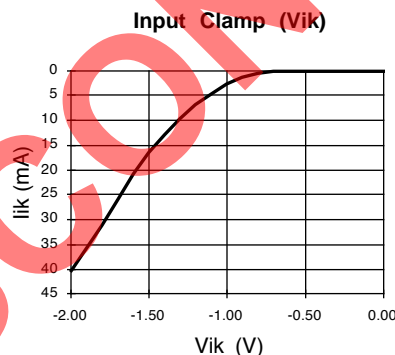
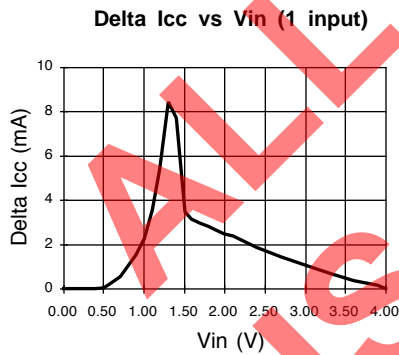
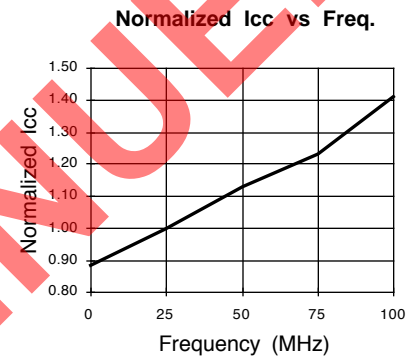
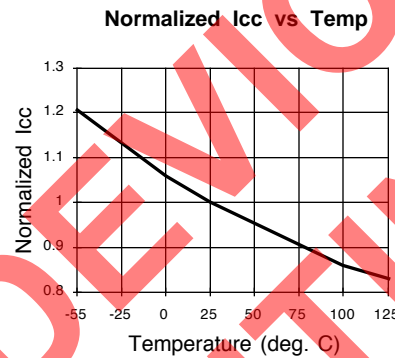
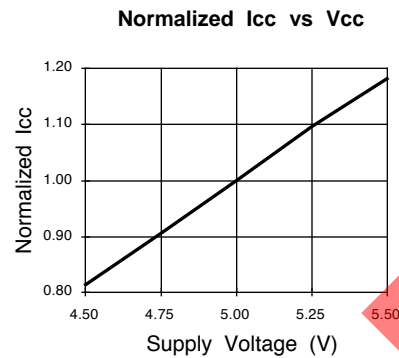
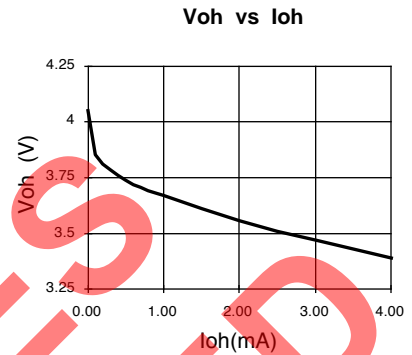
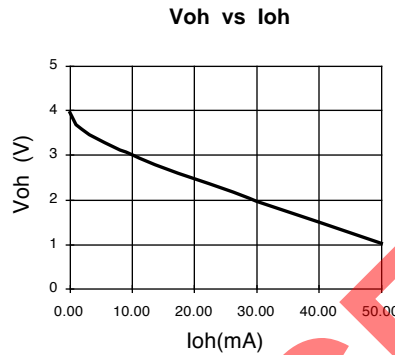
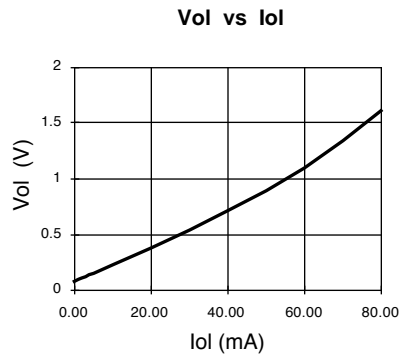
Typical Input



Typ.  $V_{ref} = 3.2V$

Typical Output

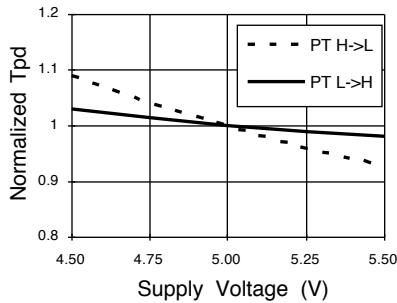
**GAL20V8C: Typical AC and DC Characteristic Diagrams**



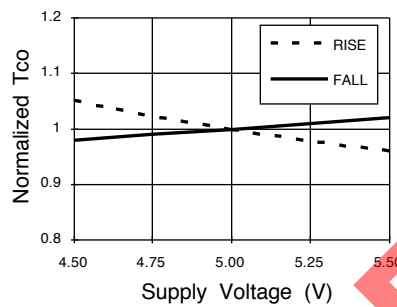


**GAL20V8B-7/-10: Typical AC and DC Characteristic Diagrams**

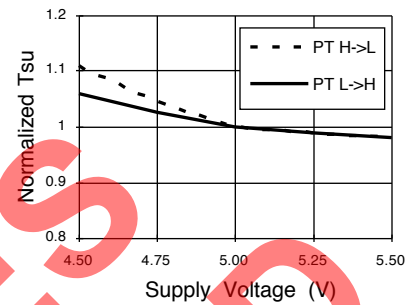
**Normalized Tpd vs Vcc**



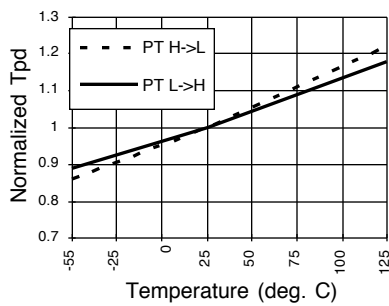
**Normalized Tco vs Vcc**



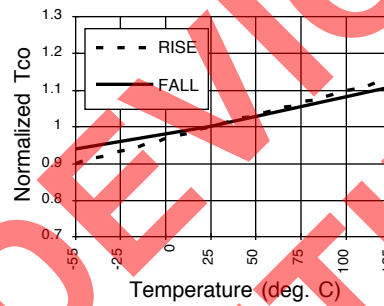
**Normalized Tsu vs Vcc**



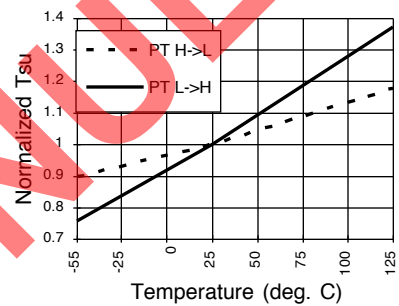
**Normalized Tpd vs Temp**



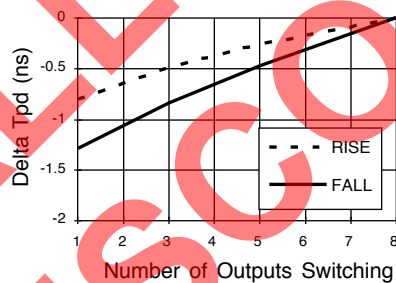
**Normalized Tco vs Temp**



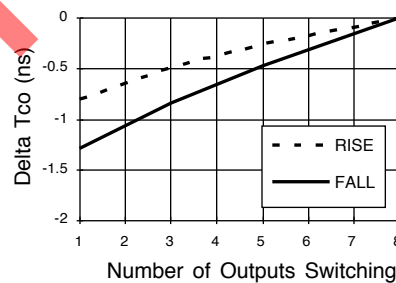
**Normalized Tsu vs Temp**



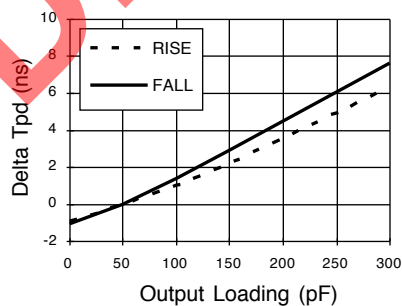
**Delta Tpd vs # of Outputs Switching**



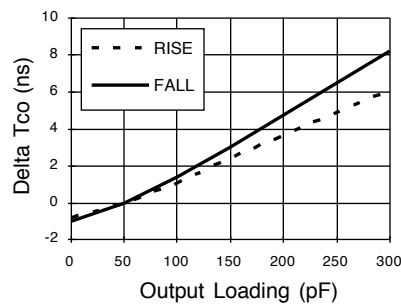
**Delta Tco vs # of Outputs Switching**



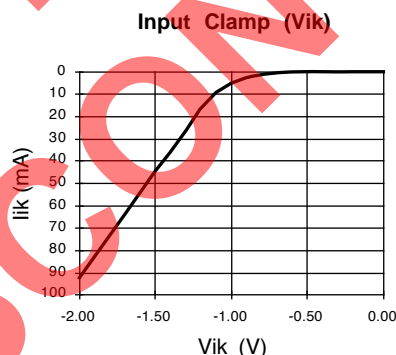
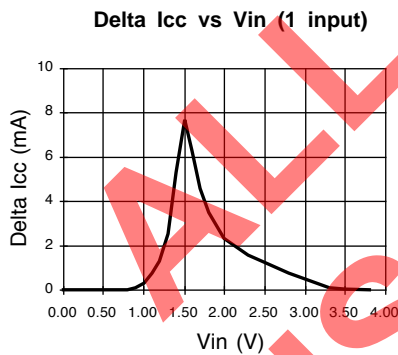
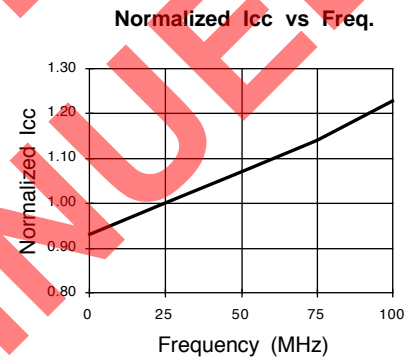
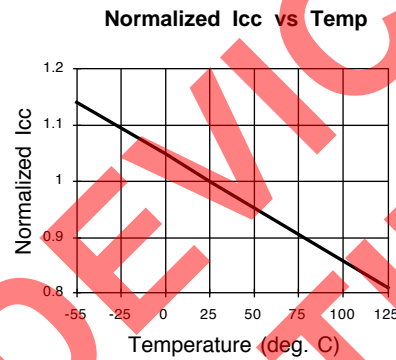
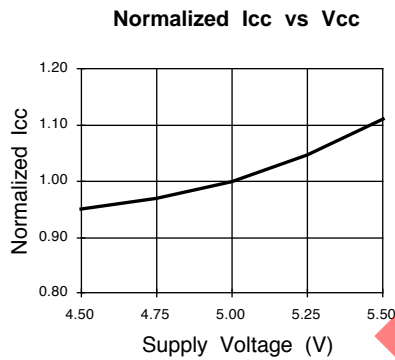
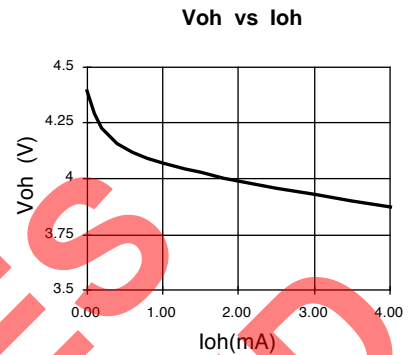
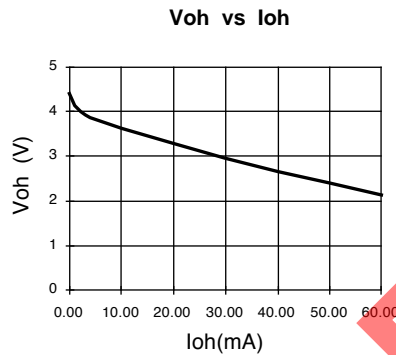
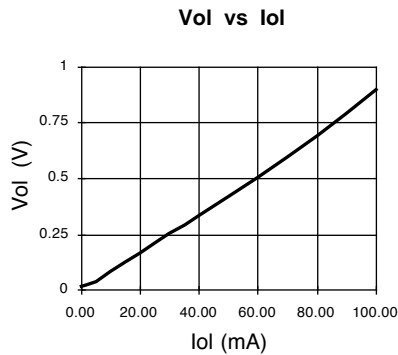
**Delta Tpd vs Output Loading**



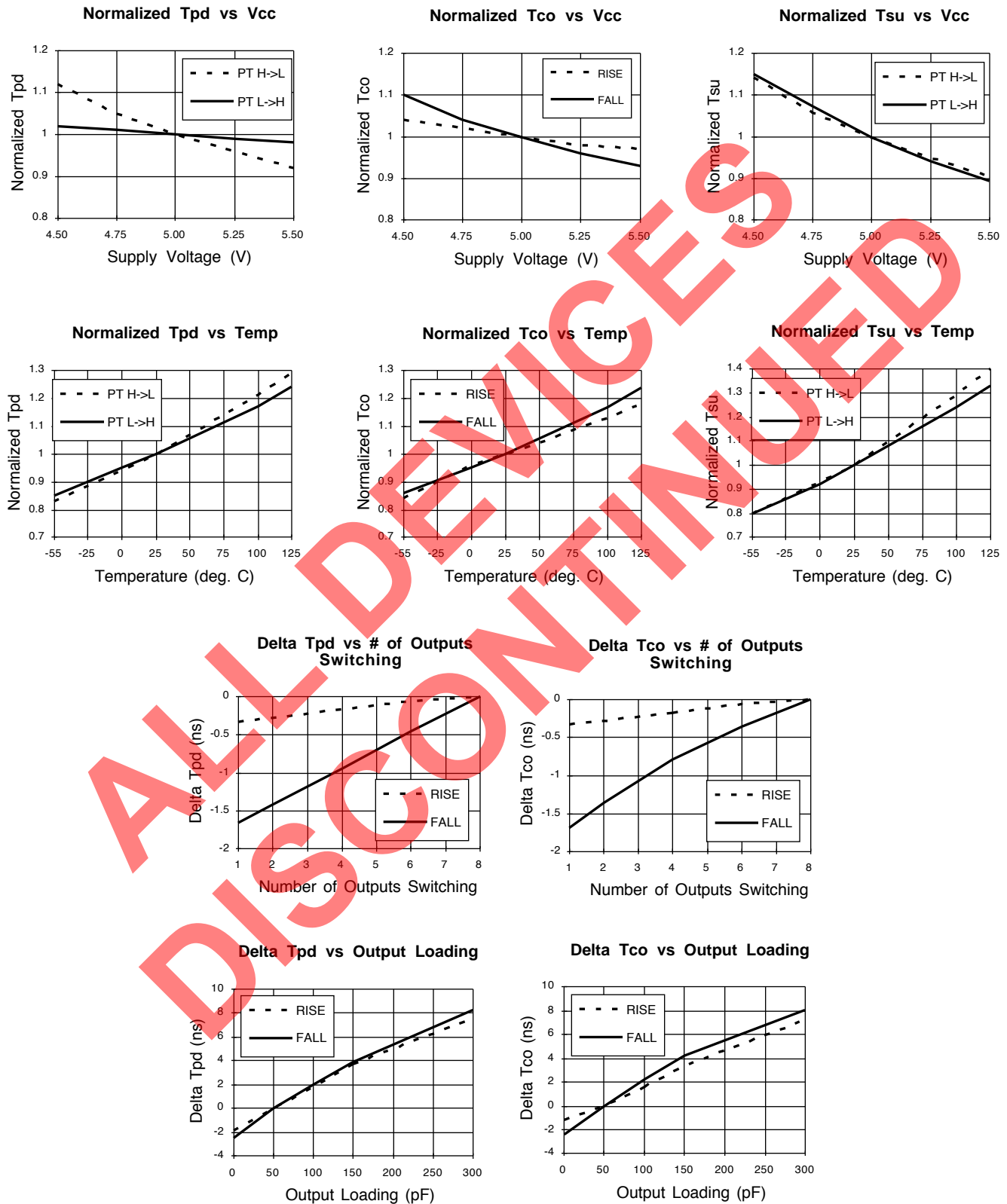
**Delta Tco vs Output Loading**



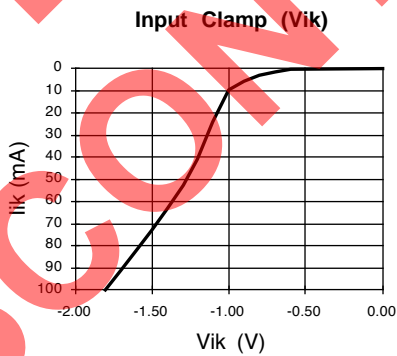
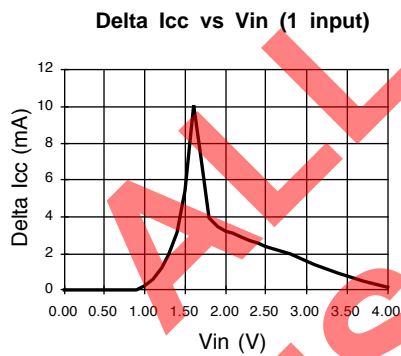
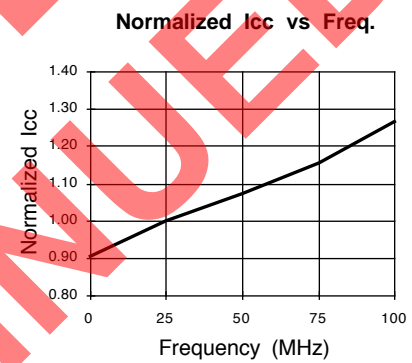
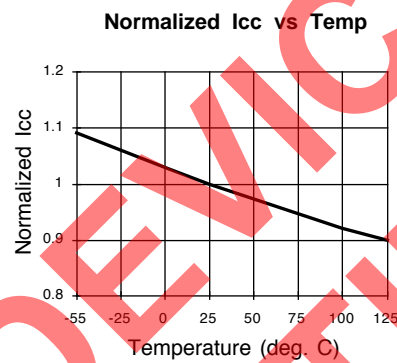
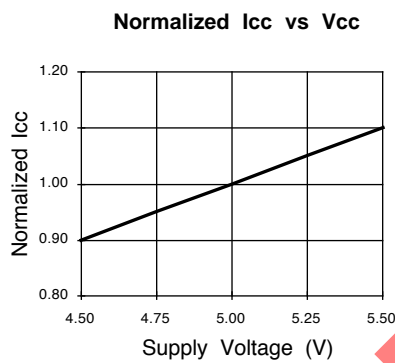
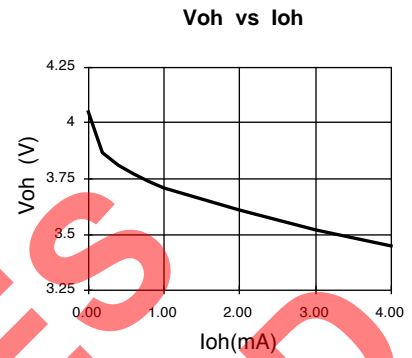
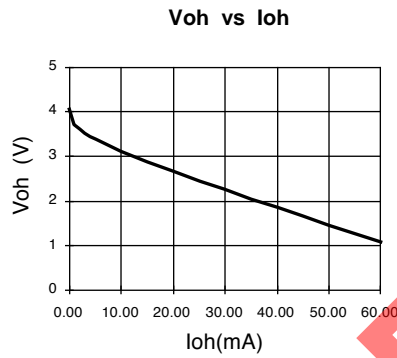
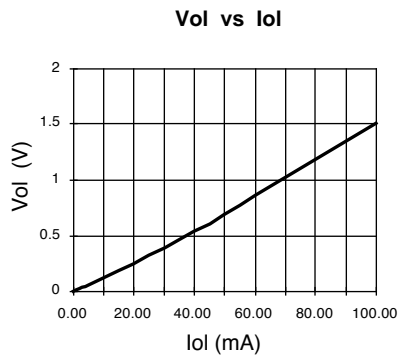
**GAL20V8B-7/-10: Typical AC and DC Characteristic Diagrams**



**GAL20V8B-15/-25: Typical AC and DC Characteristic Diagrams**



**GAL20V8B-15/-25: Typical AC and DC Characteristic Diagrams**



**Revision History**

Date	Version	Change Summary
-	20v8_06	Previous Lattice release.
August 2006	20v8_07	Updated for lead-free package options.

ALL DEVICES  
DISCONTINUED